

August 2009
SupreMOS<sup>TM</sup>

## FCP16N60N / FCPF16N60NT

# N-Channel MOSFET 600V, 16A, $0.170\Omega$

#### **Features**

- $R_{DS(on)} = 0.17\Omega$  ( Typ.)@  $V_{GS} = 10V$ ,  $I_D = 8A$
- Ultra low gate charge (Typ. Qg = 40.2nC)
- · Low effective output capacitance
- 100% avalanche tested
- · RoHS compliant



#### **Description**

The SupreMOS MOSFET, Fairchild's next generation of high voltage super-junction MOSFETs, employs a deep trench filling process that differentiates it from preceding multi-epi based technologies. By utilizing this advanced technology and precise process control, SupreMOS provides world class Rsp, superior switching performance and ruggedness.

This SupreMOS MOSFET fits the industry's AC-DC SMPS requirements for PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.



#### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FCP16N60N	FCPF16N60NT	Units
V <sub>DSS</sub>	Drain to Source Voltage				V	
V <sub>GSS</sub>	Gate to Source Voltage		:	±30	V	
1	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		16.0	16.0*	۸
ID	Diain Current	-Continuous (T <sub>C</sub> = 100°C)		10.1	10.1*	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	48.0	48.0*	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		2) 355		mJ	
I <sub>AR</sub>	Avalanche Current		5.3		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy 1.34			1.34	mJ	
dv/dt	MOSFET dv/dt Ruggedne	ess		100		V/ns
uv/ui	Peak Diode Recovery dv/	dt	(Note 3)	) 20		V/ns
n	Dower Dissipation	(T <sub>C</sub> = 25°C)		134.4	35.7	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.08	0.29	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range -55 to +150		οС			
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			°C		

<sup>\*</sup>Drain current limited by maximum junction temperature

#### **Thermal Characteristics**

Symbol	Parameter	FCP16N60N	FCPF16N60NT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case		3.5	
$R_{\theta CS}$	Thermal Resistance, Case to Heat Sink (Typical) 0.5 0.5			°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCP16N60N	FCP16N60N	TO-220	-	-	50
FCPF16N60NT	FCPF16N60NT	TO-220F	-	-	50

### **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Parameter Test Conditions		Min.	Тур.	Max.	Units
cteristics					
Drain to Source Breakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}, T_C = 25^{\circ}\text{C}$	600	-	-	V
Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, Referenced to 25°C	-	0.73	-	V/ºC
Zara Cata Valtaga Prain Current	$V_{DS} = 480V, V_{GS} = 0V$	-	-	10	
Zero Gate Voltage Drain Current	$V_{DS} = 480V, V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA
	Cteristics  Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient  Zero Gate Voltage Drain Current				

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_{D} = 8A$	-	0.170	0.199	Ω
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40V, I_{D} = 8A$	-	13	-	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	$V_{DS} = 100V, V_{GS} = 0V$ f = 1MHz		1630	2170	pF
C <sub>oss</sub>	Output Capacitance			70	95	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			5	10	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380V, V_{GS} = 0V, f = 1MHz$		40	60	pF
C <sub>oss</sub> eff.	Effective Output Capacitance	vacitance $V_{DS} = 0V$ to 480V, $V_{GS} = 0V$		176	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	40.2	52.3	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 380V, I_{D} = 8A,$	-	6.7	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Note 4)	-	12.9	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open		2.9		Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	15.8	41.6	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380V, I_D = 8A$				41.0	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 4.7\Omega$		-	60.3	130.6	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	20.2	50.4	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	16	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	48	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 8A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 8A	-	319	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	4.4	-	μС

#### Notes

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.  $I_{AS}$  = 5.3A,  $R_G$  = 25 $\Omega$ , Starting  $T_J$  = 25 $^{\circ}C$
- 3. I\_{SD}  $\leq$  16A, di/dt  $\leq$  200A/ $\mu s,~V_{DD}$  = 380V, Starting T  $_J$  = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

#### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

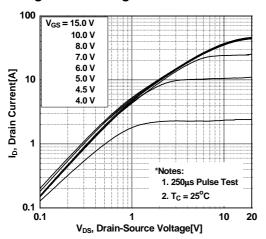


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

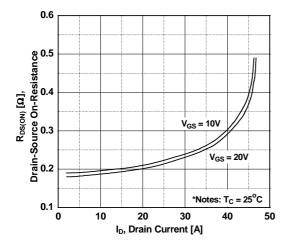


Figure 5. Capacitance Characteristics

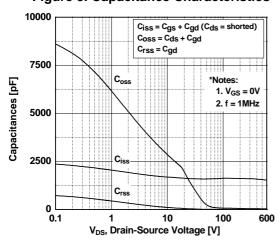


Figure 2. Transfer Characteristics

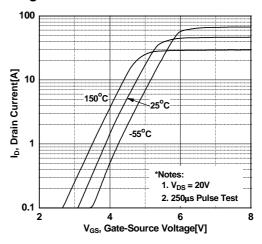
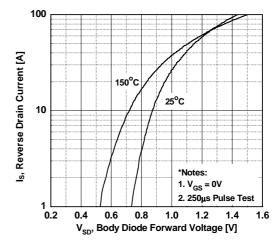
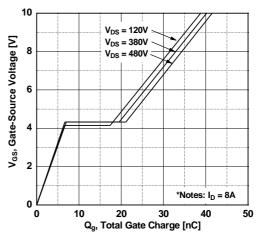


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature



**Figure 6. Gate Charge Characteristics** 



#### **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

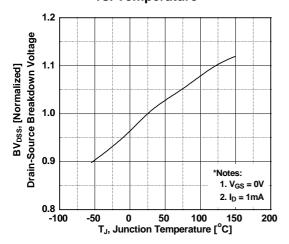


Figure 9. Maximum Safe Operating Area \_ FCP16N60N

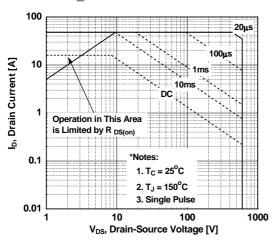


Figure 11. Maximum Drain Current vs. Case Temperature

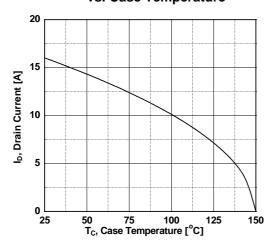


Figure 8. On-Resistance Variation vs. Temperature

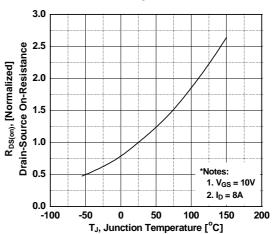
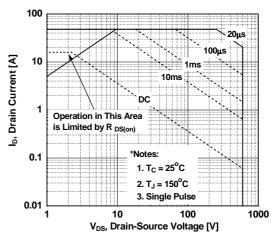


Figure 10. Maximum Safe Operating Area \_ FCPF16N60NT



#### **Typical Performance Characteristics (Continued)**

Figure 12. Transient Thermal Response Curve \_ FCP16N60N

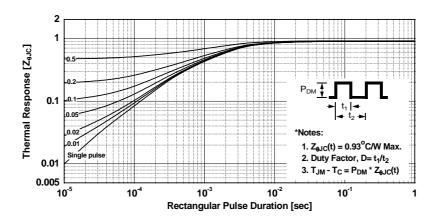
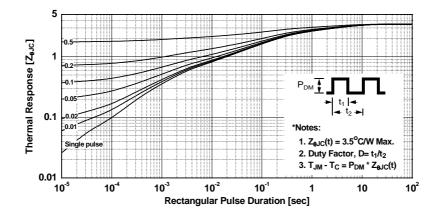
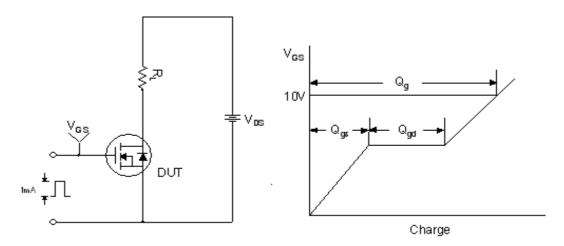


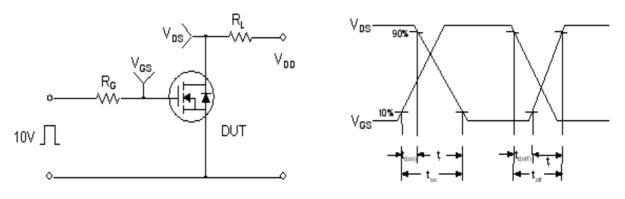
Figure 13. Transient Thermal Response Curve \_ FCPF16N60NT



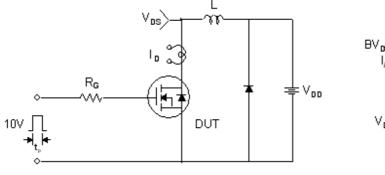
#### **Gate Charge Test Circuit & Waveform**

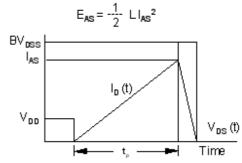


#### **Resistive Switching Test Circuit & Waveforms**

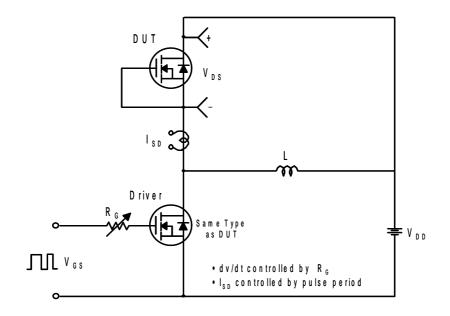


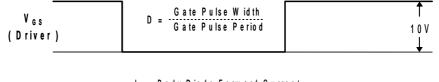
**Unclamped Inductive Switching Test Circuit & Waveforms** 

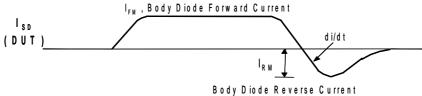


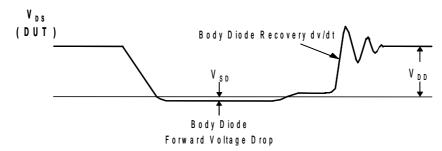


#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



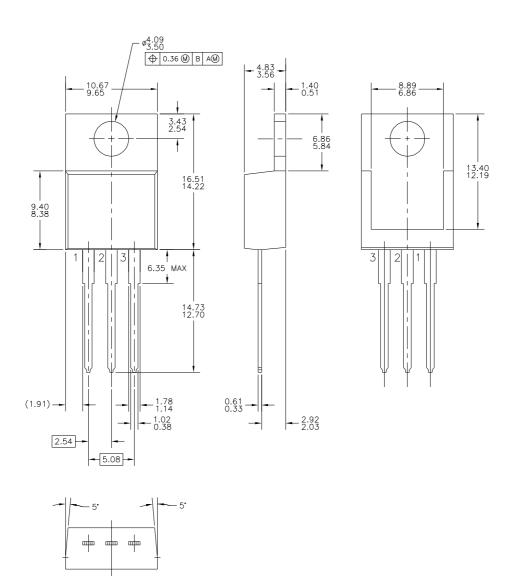






#### **Mechanical Dimensions**

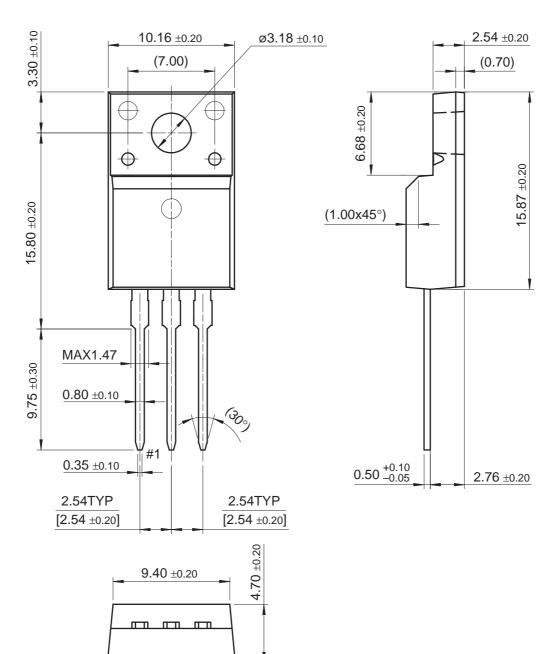
TO-220



Dimensions in Millimeters

#### **Mechanical Dimensions**

## TO-220F



Dimensions in Millimeters



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